

Notice of References Cited	Application/Control No. 10/600,377	Applicant(s)/Patent Under Reexamination HOU ET AL.	
	Examiner Duy-Vu N. Deo	Art Unit 1765	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,207,565	03-2001	Yeh et al.	438/669
	B	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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